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- 95-mΩ Maximum (5-V Input) High-Side MOSFET Switch
- Short-Circuit Protection and Thermal Protection
- Logic Overcurrent Output
- 4-V to 7-V Operating Range
- Enable Input Compatible With 3-V and 5-V Logic
- Controlled Rise and Fall Times Limit Current Surges and Minimize EMI
- Undervoltage Lockout Ensures That Switch is Off at Start-Up
- 10-μA Maximum Standby Current
- Available in Space-Saving 8-Pin SOIC and 8-Pin PDIP
- 0°C to 125°C Operating Junction Temperature Range
- 12-kV Output, 6-kV Input Electrostatic-Discharge Protection

description

The TPS2014 and TPS2015 power distribution switches are intended for applications where heavy capacitive loads and short circuits are likely to be encountered. The high-side switch is a 95-m Ω n-channel MOSFET. The switch is controlled by a logic enable that is compatible with 3-V and 5-V logic. Gate drive is provided by an internal charge pump designed to control the power switch rise times and fall times to minimize current surges during switching. The charge pump requires no external components and allows operation from supplies as low as 4 V.

When the output load exceeds the current-limit threshold or a short is present, the TPS20xx limits the output current to a safe level by switching into a constant-current mode, and the overcurrent logic output is set to low. Continuous heavy overloads and short circuits will increase the power dissipation in the switch and cause the junction temperature to rise. A thermal protection circuit is implemented, which shuts the switch off to prevent damage when the junction temperature exceeds its thermal limit. An undervoltage lockout is provided to ensure the switch is in the off state at start-up.

The TPS2014 and TPS2015 differ only in short-circuit current limits. The TPS2014 is designed to limit at 1.2 A load and the TPS2015 limits at 2 A (see the available options table). The TPS20xx is available in 8-pin small-outline integrated circuit (SOIC) and 8-pin PDIP packages, and operates over a junction temperature range of 0°C to 125°C.

		RECOMMENDED MAXIMUM	TYPICAL SHORT-CIRCUIT	PACKAGE	D DEVICES	CHIP FORM
	т _А	CONTINUOUS LOAD CURRENT	CURRENT LIMIT AT 25°C	SOIC (D) [†]	PDIP (P)	(Y)
	0°C TO 85°C	0.6 A	1.2 A	TPS2014D	TPS2014P	TPS2014Y
	0 0 10 85 0	1 A	2 A	TPS2015D	TPS2015P	TPS2015Y

AVAILABLE OPTIONS

[†] The D package is available taped and reeled. Add an R suffix to device type (e.g., TPS2014DR).



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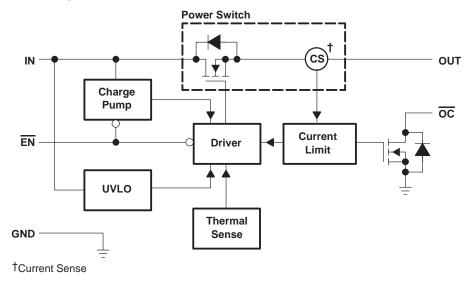
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D OR P PACKAGE (TOP VIEW)										
GND [IN [IN [EN [0 1 2 3 4	8 7 6 5] OUT] OUT] OUT] OC							

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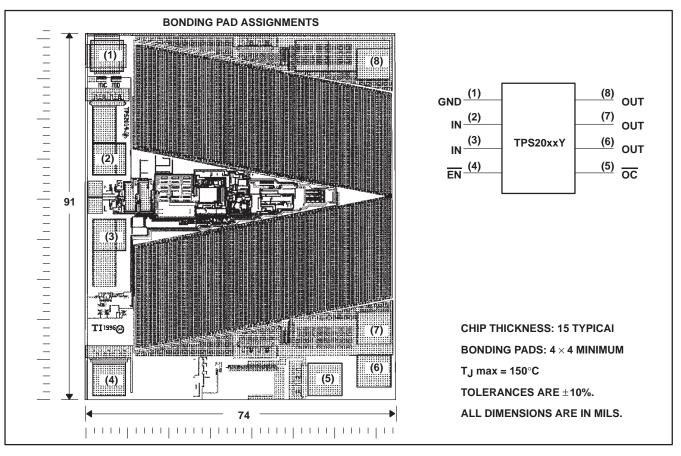
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functional block diagram



TPS20xxY chip information

This chip, when properly assembled, displays characteristics similar to those of the TPS20xx. Ultrasonic bonding may be used on the doped aluminium bonding pads. The chip may be mounted with conductive epoxy or a gold-silicon preform.





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TERM	INAL	1/0	DESCRIPTION				
NAME	NO.	1/0	DESCRIPTION				
EN	4	Ι	Enable input. Logic low at EN turns the power switch on.				
GND	1	Ι	Ground				
IN	2, 3	Т	Input voltage				
OC	5	0	OC is asserted active low during a fault condition.				
OUT	6–8	0	Power switch output				

Terminal Functions

detailed description

power switch

The power switch is an n-channel MOSFET with a maximum on-state resistance of 95 m Ω (V_{I(IN)} = 5 V), configured as a high-side switch.

charge pump

An internal 100-kHz charge pump supplies power to the driver circuit and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 4 V and requires very little supply current.

driver

The driver controls the gate voltage of the power switch. To limit large current surges and reduce the associated electromagnetic interference (EMI) produced, the driver incorporates circuitry that controls the rise times and fall times of the output voltage. The rise and fall times are typically in the 2-ms to 4-ms range instead of the microsecond or nanosecond range for a standard FET.

enable (EN)

A logic high on \overline{EN} turns off the power switch and the bias for the charge pump, driver, and other circuitry to reduce the supply current to less than 10 μ A. A logic zero input restores bias to the drive and control circuits and turns the power on. The enable input is compatible with both TTL and CMOS logic levels.

overcurrent (OC)

OC is an open-drain logic output that is asserted (active low) when an overload or short circuit is encountered. The output remains asserted until the overload or short-circuit condition is removed.

current sense

A sense FET monitors the current supplied to the load. The sense FET provides a much more efficient way to measure current than conventional resistance methods. When an overload or short circuit is encountered, the current-sense circuitry sends a control signal to the driver. The driver in turn reduces the gate voltage and drives the power FET into its linear region, which switches the output into a constant current mode and simply holds the current constant while varying the voltage on the load.

thermal sense

An internal thermal-sense circuit shuts off the power switch when the junction temperature rises to approximately to 180°C. Hysteresis is built into the thermal sense circuit. After the device has cooled approximately 20°C, the switch turns back on. The switch continues to cycle off and on until the fault is removed.

undervoltage lockout

An internal voltage sense monitors the input voltage. When the input voltage is below 3.2 V nominal, a control signal turns off the power switch.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Input voltage range, V _I (see Note1)	
Output voltage range, V _O (see Note1)	–0.3 V to V _{I(IN)} + 0.3 V
Input voltage range, VI at EN	–0.3 V to 7 V
Continuous output current, I _O	internally limited
Continuous total power dissipation	. See Dissipation Rating Table
Operating virtual junction temperature range, T _J	0°C to 125°C
Storage temperature range, T _{stg}	65°C to 150°C
Lead temperature soldering 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages are with respect to GND.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 125°C POWER RATING
Р	1175 mW	9.4 mW/°C	752 mW	235 mW
D	725 mW	5.8 mW/°C	464 mW	145 mW

recommended operating conditions

		MIN	MAX	UNIT
Input voltage, V _I		4	5.5	V
Input voltage, VI at EN		0	5.5	V
	TPS2014	0	0 5.5	٨
Continuous output current, IO	TPS2015	0	1	A
perating virtual junction temperature, TJ		0	125	°C

electrical characteristics over recommended operating junction temperature range, $V_{I(IN)}$ = 5.5 V, I_O = rated current, EN = 0 V (unless otherwise noted)

power switch

	PARAMETER	TE	EST CONDITIC	ons†	MIN	TYP	MAX	UNIT
		V _I = 5.5 V,	TJ = 25°C			75	95	
	On-state resistance	V _I = 5 V,	TJ = 25°C			80	95	mΩ
ron	On-state resistance	V _I = 4.5V,	TJ = 25°C			90	110	11122
		V _I = 4 V,	TJ = 25°C			96	110	
	Leakage current, output	$\overline{EN} = V_{I},$	T _J = 25°C			0.001	1	
likg		EN = VI,	$0^{\circ}C \leq T_J \leq 1$	25°C			10	μA
	Disc time output	V _I = 5.5 V,	TJ = 25°C	CL = 1 μF		4		
tr	Rise time, output	V _I = 4 V,	TJ = 25°C	CL = 1 μF		3.8		ms
4.		V _I = 5.5 V,	TJ = 25°C	CL = 1 μF		3.9		
tf	Fall time, output	V _I = 4 V,	TJ = 25°C	CL = 1 μF		3.5		ms

[†] Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.



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electrical characteristics over recommended operating junction temperature range, $V_{I(IN)}$ = 5.5 V, I_O = rated current, \overline{EN} = 0 V (unless otherwise noted) (continued)

enable input (EN)

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
V_{IH}	High-level input voltage	$4~V \leq V_{I} \leq 5.5~V$	2		V
VIL	Low-level input voltage	$4~V \leq V_{I} \leq 5.5~V$		0.8	V
Ιį	Input current	$\overline{\text{EN}} = 0 \text{ V or } \overline{\text{EN}} = \text{V}_{I}$	-0.5	0.5	μA
^t PLH	Propagation (delay) time, low to high output	$C_L = 1 \ \mu F$		20	m 0
^t PHL	Propagation (delay) time, high to low output	$C_L = 1 \ \mu F$		40	ms

current limit

PARAMETER		TEST CONDITIONS [†]		MIN	TYP	MAX	UNIT	
Γ	laa	Short-circuit output current		TPS2014	0.66	1.2	1.8	^
	IOS	Short-circuit output current	$T_{J} = 25^{\circ}C, V_{I} = 5.5 V$	TPS2015	1.1	2	3	А

[†] Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.

supply current

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
	Supply ourrent low lovel output				0.015	10	
IDDL	Supply current, low-level output	$EN = V_{I}$	$0^\circ C \leq T_J \leq 125^\circ C$			10	μA
	Supply ourrent high lovel output	$\overline{EN} = 0 V$	TJ = 25°C		73	100	
IDDH	Supply current, high-level output		$0^\circ C \leq T_J \leq 125^\circ C$			100	μA

undervoltage lockout

PARAMETER	MIN	TYP	MAX	UNIT
VIL Low-level input voltage	2	3.2	4	V

00

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
IOS	Short-circuit output current	$0^{\circ}C \leq T_J \leq 125^{\circ}C$			5	~^^
VOL	Low-level output voltage	$0^{\circ}C \leq T_J \leq 125^{\circ}C$			0.3	mA



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electrical characteristics over recommended operating junction temperature range, $V_{I(IN)}$ = 5.5 V, I_O = rated current, \overline{EN} = 0 V (unless otherwise noted)

power switch

	PARAMETER TEST CONDITIONS ^T			Net	TPS2014Y, TPS2015Y			UNIT
	PARAMETER		TEST CONDITIONS!			TYP	MAX	UNIT
		V _I = 5.5 V,	TJ = 25°C			75		
	On-state resistance	V _I = 5 V,	TJ = 25°C			80		mΩ
ron	On-state resistance	V _I = 4.5V,	TJ = 25°C			90		11152
		V _I = 4 V,	TJ = 25°C			96		
1		$EN = V_I$,	Tj = 25°C		0.001			
likg	Leakage current, output	$\overline{EN} = V_{I},$	$0^\circ C \leq T_J \leq 1$	25°C		10		μA
	Rise time, output	V _I = 5.5 V,	TJ = 25°C	CL = 1 μF		4		
tr	Rise time, ouput	V _I = 4 V,	TJ = 25°C	CL = 1 μF		3.8		ms
+.	Fall time, output	V _I = 5.5 V,	TJ = 25°C	$C_L = 1 \ \mu F$		3.9		me
tf		V _I = 4 V,	TJ = 25°C	CL = 1 μF		3.5		ms

[†] Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.

enable input (EN)

	PARAMETER	TEST CONDITIONS	TPS2014Y, TPS2015Y			UNIT
	FARAWETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VIH	High-level input voltage	$4~V \leq V_I \leq 5.5~V$		2		V
VIL	Low-level input voltage	$4~V \leq V_I \leq 5.5~V$		0.8		V
Ц	Input current	$\overline{\text{EN}} = 0 \text{ V or } \overline{\text{EN}} = \text{V}_{I}$		0.5		μA
^t PLH	Propagation (delay) time, low to high output	C _L = 1 μF		20		
^t PHL	Propagation (delay) time, high to low output	C _L = 1 μF		40		ms

current limit

PARAMETER		TEST CONDIT	IONET	TPS2014Y, TPS2015Y			UNIT
		TEST CONDIT		MIN TYP M			UNIT
	Short-circuit output current	T 25°C . V 5 5 .V.	TPS2014		1.2		Δ
los	Short-circuit output current	$T_{J} = 25^{\circ}C, V_{I} = 5.5 V$	TPS2015		2		A

[†] Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.

supply current

PARAMETER		TEST CONDITIONS		TPS2014Y, TPS2015Y			UNIT
		TESTCO	MIN	TYP	MAX	UNIT	
1	Cumply surgest law layed surface	$\overline{EN} = V_{I} \qquad \qquad \frac{T_{J} = 25^{\circ}C}{0^{\circ}C \le T_{J} \le 125^{\circ}C}$	$T_J = 25^{\circ}C$		0.015	0.015	
IDDL	Supply current, low-level output		$0^{\circ}C \leq T_J \leq 125^{\circ}C$		10		μA
1	Supply ourrent high lovel output	$\overline{EN} = 0 V$	$T_J = 25^{\circ}C$		73		
¹ DDH	Supply current, high-level output		$0^{\circ}C \leq T_{J} \leq 125^{\circ}C$	C 1	100		μA

undervoltage lockout

	PARAMETER		TPS2014Y, TPS2015Y		
			TYP	MAX	UNIT
V_{IL}	Low-level input voltage		3.2		V



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electrical characteristics over recommended operating junction temperature range, $V_{I(IN)}$ = 5.5 V, I_O = rated current, \overline{EN} = 0 V (unless otherwise noted) (continued)

<u>0C</u>

	PARAMETER	TEST CONDITIONS	TPS2014Y, TPS2015Y	UNIT		
	FARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
IOS	Short-circuit output current	$0^{\circ}C \leq T_J \leq 125^{\circ}C$		5		~^
VOL	Low-level output voltage	$0^{\circ}C \leq T_{J} \leq 125^{\circ}C$	0.3		mA	

PARAMETER MEASUREMENT INFORMATION

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TPS2014 Threshold Current, VI(IN) = 5 V	5
TPS2015 Threshold Current, VI(IN) = 5 V	6
TPS2014 (Enabled) into Short Circuit, VI(IN) = 5 V	7
TPS2015 (Enabled) into Short Circuit, V _{I(IN)} = 5 V	8

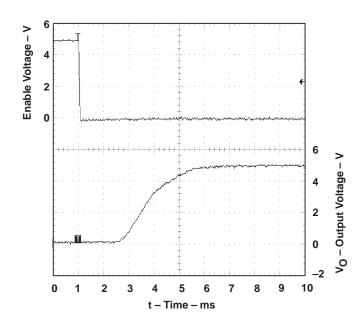


Figure 1. Propagation Delay and Rise Time With 1- μ F Load, V_{I(IN)} = 5 V



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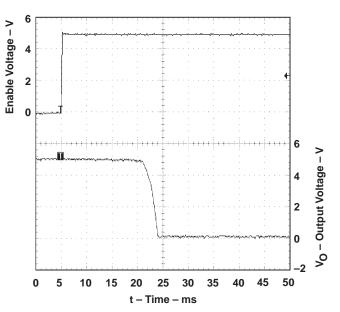


Figure 2. Propagation Delay and Fall Time With 1- μ F Load, V_{I(IN)} = 5 V

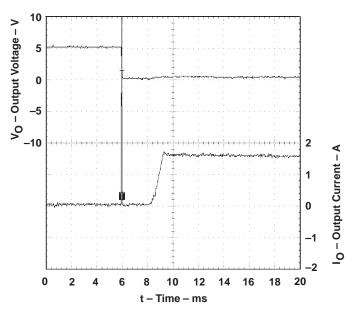


Figure 3. TPS2014 Short-Circuit Current. Short is Applied to Enabled Device, V_{I(IN)} = 5 V



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PARAMETER MEASUREMENT INFORMATION

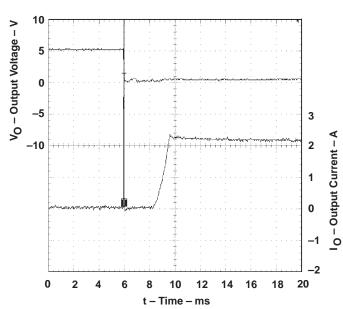


Figure 4. TPS2015 Short-Circuit Current. Short is Applied to Enabled Device, V_{I(IN)} = 5 V

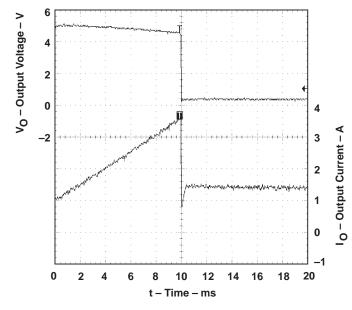
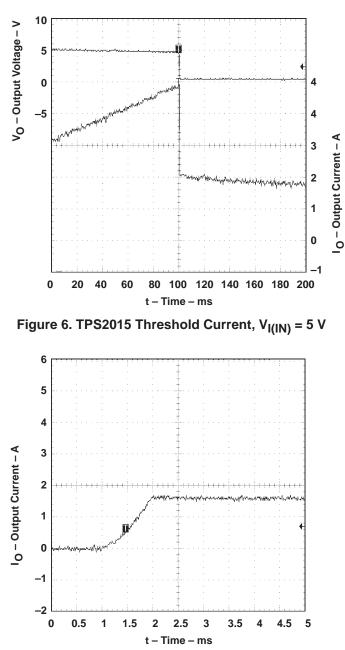


Figure 5. TPS2014 Threshold Current, VI(IN) = 5 V



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PARAMETER MEASUREMENT INFORMATION

Figure 7. TPS2014 (Enabled) into Short Circuit, V_{I(IN)} = 5 V



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PARAMETER MEASUREMENT INFORMATION

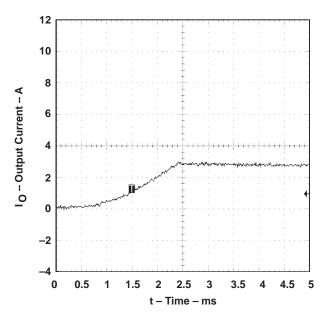


Figure 8. TPS2015 (Enabled) into Short Circuit, V_{I(IN)} = 5 V

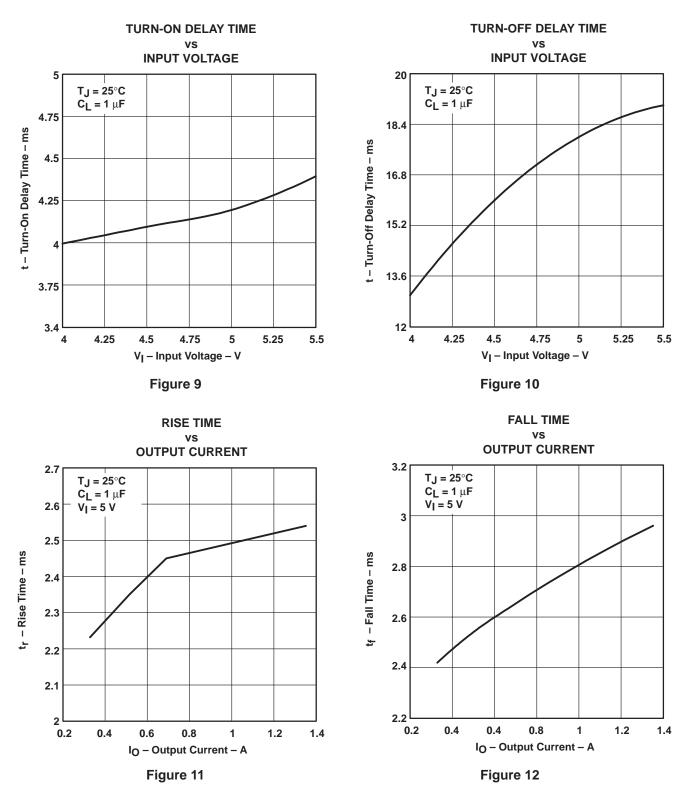
TYPICAL CHARACTERISTICS

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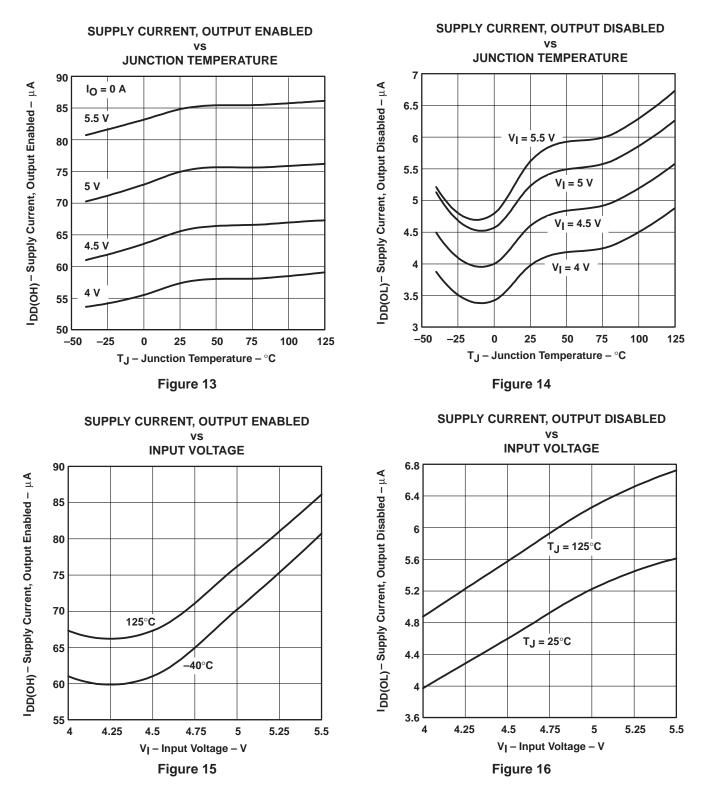


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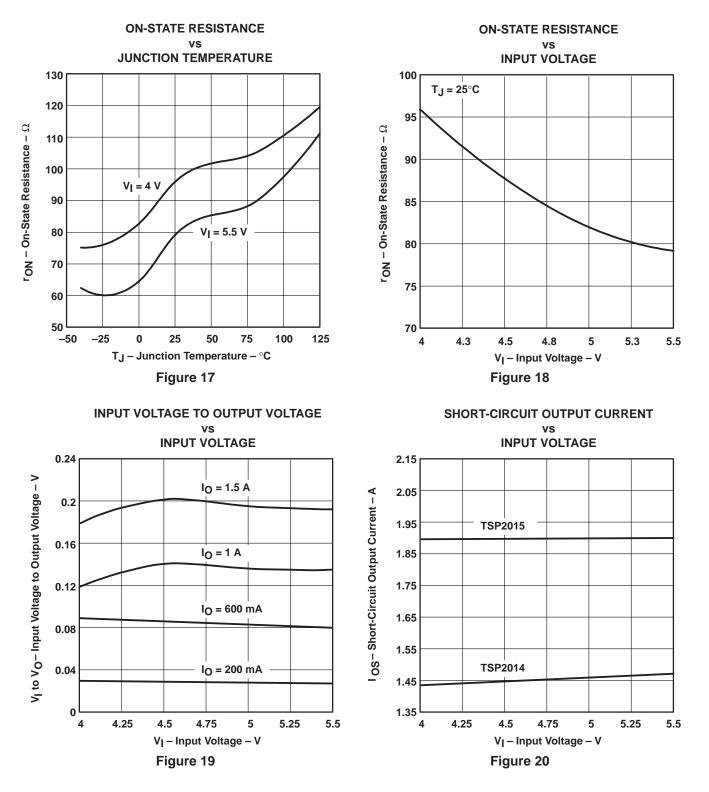


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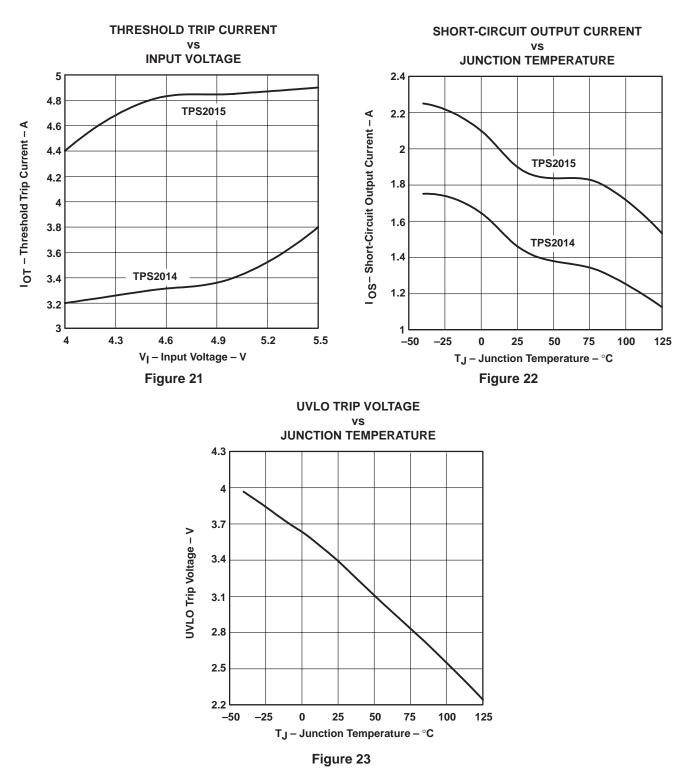


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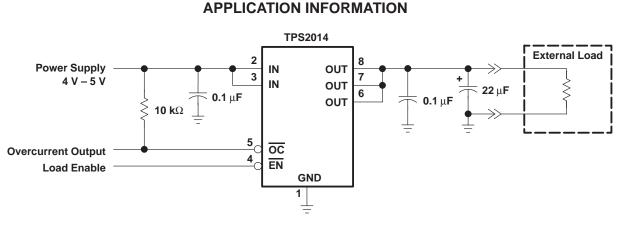


Figure 24. Typical Application

power supply considerations

The TPS20xx has multiple inputs and outputs that must be connected in parallel to minimize voltage drop and prevent unnecessary power dissipation.

A 0.1- μ F ceramic bypass capacitor between IN and GND, close to the device, is recommended. A high-value electrolytic capacitor is also desirable when the output load is heavy or has large paralleled capacitors. Bypassing the output with a 0.1- μ F ceramic capacitor improves the immunity of the device to electrostatic discharge (ESD).

overcurrent

A sense FET is employed to check for overcurrent conditions. Unlike sense resistors and polyfuses, sense FETs do not increase series resistance to the current path. When an overcurrent condition is detected, the device maintains a constant output current and reduces the output voltage accordingly. Shutdown only occurs when the fault is present long enough to activate thermal limiting.

Three possible overload conditions can occur. In the first condition, the output has been shorted before the device is enabled or before $V_{I(IN)}$ has been applied (see Figures 7 and 8). The TPS20xx senses the short and immediately switches into a constant-current output.

Under the second condition, the short occurs while the device is enabled. At the instant the short occurs, very high currents flow for a short time before the current-limit circuit can react (see Figures 3 and 4). After the current-limit circuit has tripped, the device limits normally.

Under the third condition, the load has been gradually increased beyond the recommended operating current. The current is permitted to rise until the current-limit threshold is reached (see Figures 5 and 6). The TPS20xx is capable of delivering current up to the current-limit threshold without damage. When the threshold has been reached, the device switches into its constant-current mode.



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APPLICATION INFORMATION

power dissipation and junction temperature

The low on-resistance of the n-channel MOSFET allows small surface-mount packages, such as SOIC, to pass large currents. The thermal resistance of these packages is high compared to that of power packages; it is good design practice to check power dissipation and junction temperature. The first step is to find r_{on} at the input voltage and at the operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read r_{on} from Figure 17. Next calculate the power dissipation using:

$$P_{D} = r_{on} \times I^{2}$$

Finally, calculate the junction temperature:

$$T_J = P_D \times R_{\theta JA} + T_A$$

Where:

 T_A = Ambient temperature

 $R_{\theta JA}$ = Thermal resistance SOIC = 172°C/W, P = 106°C/W

Compare the calculated junction temperature with the initial estimate. If they do not agree within a few degrees, repeat the calculation using the calculated value as the new estimate. Two or three iterations are generally sufficient to get a reasonable answer.

thermal protection

Thermal protection is provided to prevent damage to the IC when heavy-overload or a short-circuit fault is present for an extended period of time. The fault forces the TPS20xx into constant current mode, which causes the voltage across the high-side switch to increase. Under short-circuit conditions, the voltage across the switch is equal to the input voltage. The increased dissipation causes the junction temperature to rise to dangerously high levels. The protection circuit senses the junction temperature of the switch and shuts it off. The switch remains off until the junction temperature has dropped approximately 20°C. The switch continues to cycle in this manner until the load fault or the input power is removed.

undervoltage lockout

An undervoltage lockout is provided to ensure that the power switch is in the off state at power up. Whenever the input voltage falls below approximately 3.2 V, the power switch quickly turns off. This facilitates the design of hot-insertion systems that may not have the ability to turn off the power switch before input power is removed. Upon reapplication of the input voltage (if enabled), the power switch turns on with a controlled rise time to reduce inrush current, EMI, and voltage overshoots.

For proper operation of the UVLO, the TPS20xx requires the voltage decay from 3 V to 2 V to take at least 200 μ s. Capacitance is added to the input or output of the TPS20xx to increase this decay rate. Capacitance is generally added to the output to lower inrush current due to input capacitance.

Universal Serial Bus (USB) applications

The USB specification provides for five different classes of devices based on their power sourcing and sinking requirements. These classes of devices are: bus-powered hub, self-powered hub, lower power bus-powered function, high power bus-powered function, and self-powered functions. The TPS20xx can provide power distribution solutions for many of these devices.



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APPLICATION INFORMATION

bus-powered and self-power hubs

Hubs provide data and power for downstream functions through output ports. Self-power hubs have internal power supplies that furnish power to downstream functions. Each port is required to supply 500 mA continuous to a downstream function. Each port must have overcurrent protection to meet the requlatory safety limit that no single port can deliver more than 5 A. The self-power hub must also have a method to detect and report an overcurrent condition to the USB host. The TPS20xx provides the required current-limiting function and has an overcurrent logic output to inform the hub controller of the fault condition. The on-state resistance of the TPS20xx is low enough to meet all USB voltage regulation requirements. The switch also provides the capability to remove power from a faulted port.

Bus-powered hubs distribute power and data from an input port to downstream ports. Each output port is required to supply 100 mA continuous. A bus-powered hub is not required to provide overcurrent protection because it is provided by the upstream port. In order to power up in a low power state, the self-powered hub must be able to switch power to its output ports. The TPS20xx can also provide this function.

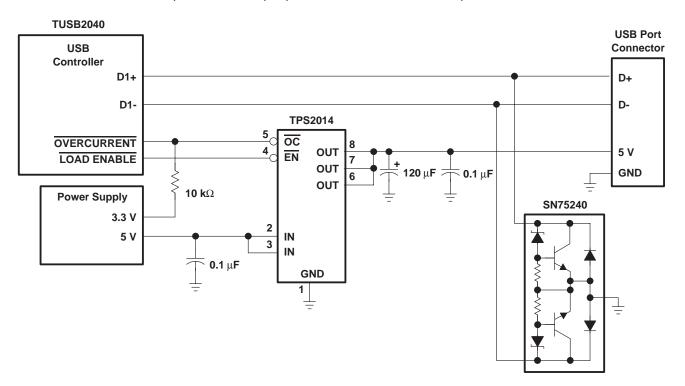


Figure 25. Typical USB Self-Powered Hub Application

low power bus-powered functions and high power bus-powered functions

Low-power and high-power bus-powered functions are powered by their input ports. If the load of the function is more than the parallel combination of 44 Ω and 10 μ F, it must implement inrush current limiting. The TPS20xx provides this function with its controlled rise time during turn on.



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USB Port Connector Internal Function D+ D+ D-D-**TPS2014** 5 oc 8 4 5 V OUT 5 V EN OUT **22** μ**F** *≂* GND GND **⊂ 0.1** μ**F** 6 OUT 2 IN 3 IN **0.1** μ**F** GND -

APPLICATION INFORMATION



ESD protection

All TPS20xx terminals incorporate ESD-protection circuitry designed to withstand a 6-kV human-body-model discharge as defined in MIL-STD-883C. Additionally, the output is protected from discharges up to 12 kV.



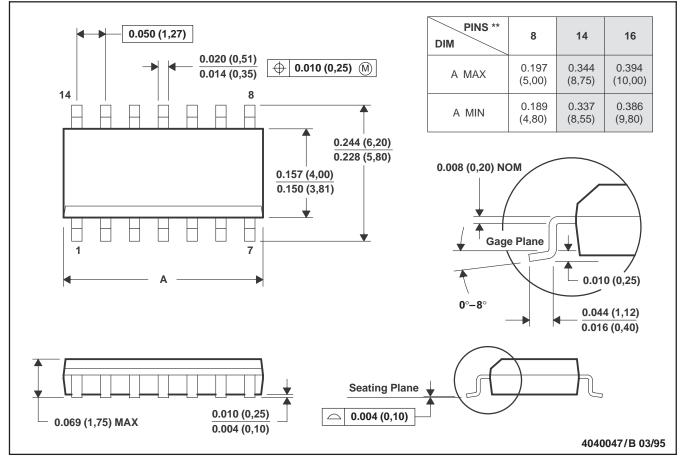
SLVS159B - DECEMBER 1996 - REVISED AUGUST 1997

MECHANICAL DATA

D (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

14 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

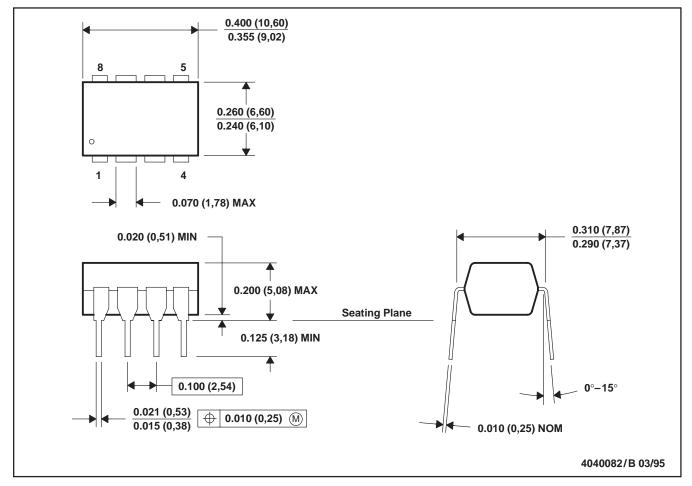
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
- D. Four center pins are connected to die mount pad.
- E. Falls within JEDEC MS-012



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MECHANICAL DATA

PLASTIC DUAL-IN-LINE PACKAGE



- NOTES: A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. Falls within JEDEC MS-001

P (R-PDIP-T8)



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